

C1  
a multi-level dielectric layer located over said lower interconnect layer;  
an upper metal interconnect layer located over said multi-level dielectric layer; and  
a thin film resistor embedded within said multi-level dielectric layer between and physically separated in a vertical direction from said lower metal interconnect layer and said upper metal interconnect layer.

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Please add claims 17 and 18.

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C2  
17. An integrated circuit comprising a semiconductor chip that comprises:  
a lower metal interconnect layer located over a semiconductor body;  
a multi-level dielectric layer located over said lower interconnect layer;  
an upper metal interconnect layer located over said multi-level dielectric layer; and  
a thin film resistor embedded within said multi-level dielectric layer between said lower metal interconnect layer and said upper metal interconnect layer.

18. The integrated circuit of claim 17, wherein the semiconductor chip further comprises:  
a first plurality of conductively filled vias extending from said upper metal interconnect layer to said lower interconnect layer; and  
a second plurality of conductively filled vias extending from said upper metal layer to said thin film resistor.

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